

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant(s) : Aaron PARTRIDGE et al.  
Serial No. : 10/713,172  
Filing Date : November 14, 2003  
For : CRACK AND RESIDUE FREE CONFORMAL  
DEPOSITED SILICON OXIDE WITH  
PREDICTABLE AND UNIFORM ETCHING  
CHARACTERISTICS  
Examiner : Francis P. Smith  
Group Art Unit : 4151  
Confirmation No. : 9823  
**Customer No. : 26646**

Mail Stop Amendment  
Commissioner for Patents  
P.O. Box 1450  
Alexandria VA 22313-1450

I hereby certify that this correspondence is being  
electronically transmitted to the United States  
Patent and Trademark Office via the Office  
electronic filing system on April 17, 2008

Signature: /Elizabeth Tretter/

**AMENDMENT**

SIR:

In response to the Office Action of January 18, 2008 (the three-month response date for is April 18, 2008), please reconsider the above-identified application based on the following.

**Amendments to the Specification** begin on page 2 of this paper.

**Amendments to the Claims** are reflected in the listing of the claims which begins on page 3 of this paper.

**Remarks** begin on page 11 of this paper.